



2016 International Symposium on Dependable Integrated Systems



November 28, 2016

Denki Building Conference C, Watanabe-Dohri 2-1-82, Chuo-Ku, Fukuoka, Japan

■ 10:00~10:10 Opening & Introduction to DISC

Xiaoqing Wen, Professor and Director of DISC, Kyushu Institute of Technology, Japan

■ 10:10~10:55 Keynote 1

• **Options and Organization of Faster-than-at-Speed-Test**

Hans-Joachim Wunderlich, Professor, University of Stuttgart, Germany

■ 10:55~11:40 Keynote 2

• **Test and Verification in the Presence of Unknowns**

Bernd Becker, Professor, University of Freiburg, Germany

■ 11:40~11:50 Break

■ 11:50~12:35 Keynote 3

• **Hardware Security and Test: Friends or Enemies?**

Ilija Poljan, Professor, University of Passau, Germany

■ 12:35~14:00 Lunch

■ 14:00~14:30 Invited Talk 1

• **Hybrid Test Compression for High Test Coverage Using Optimal Dictionaries**

Stephan Eggersgluss, Independent Post-Doctoral Researcher, University of Bremen, Germany

■ 14:30~15:00 Invited Talk 2

• **Test Strategies for Reconfigurable Scan Networks**

Micheal Kochte, Post-Doctoral Researcher, University of Stuttgart, Germany

■ 15:00~15:10 Break

■ 15:10~15:40 Invited Talk 3

• **Application of Formal Methods to the Timing Analysis of Digital Circuits**

Matthias Sauer, Post-Doctoral Researcher, University of Freiburg, Germany

■ 15:40~16:10 Lecture on Poster Presentation

*Lecturers: Stefan Holst, Assistant Professor, Kyushu Institute of Technology, Japan
Eric Schneider, Researcher, University of Stuttgart, Germany*

■ 16:10~16:40 Oral Poster Presentation

*Chair: Stefan Holst, Assistant Professor, Kyushu Institute of Technology, Japan
Eric Schneider, Researcher, University of Stuttgart, Germany*

(○: Presenter)

• **Design of ToA-based Positioning System for Industrial Wireless LAN**

Khairunisa Ahmad Denney (○), Mitsuru Hamada, Yuhei Nagao, Masayuki Kurosaki, Hiroshi Ochi

• **Unified HW/SW Framework for System-Level Evaluation**

Nana Sutisna (○), Leonardo Lanante Jr., Yujei Nagao, Masayuki Kurosaki, Hiroshi Ochi

• **Vth-Shiftable SRAM Cell TEGs for Direct Measurement for the Immunity of the Threshold Voltage Variability**

Shogo Yamaguchi (○), Hitoshi Imi, Tokumaru Shogo, Kazuyuki Nakamura

- **High Quality At-Speed Scan Test Generation**

Toshiki Miyazaki (○), Xiaoqing Wen, Kohei Miyase, Stefan Holst

- **Circuit Design for Measuring Power-Induced Delay in Scan Testing**

Masaaki Tokumoto (○), Xiaoqing Wen, Kohei Miyase, Stefan Holst

- **On A Temperature and Voltage Monitor with 65nm CMOS Technology**

Kenji Inoue (○), Seiji Kajihara

■ 16:40~17:40 **Poster and Reception**

■ 17:40~17:45 **Closing**

Seiji Kajihara, Professor, Kyushu Institute of Technology, Japan